

# 8822 Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor

## **General Description**

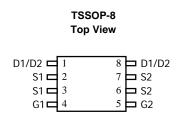
The 8822 uses advanced trench technology to provide excellent  $R_{\rm DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V  $V_{\rm GS(MAX)}$  rating. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration. Standard Product 8822 is Pb-free (meets ROHS & Sony 259 specifications). 8822 is a Green Product ordering option. 8822 is electrically identical.

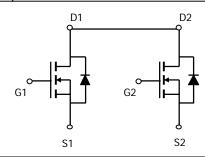
### **Features**

$$V_{DS}(V) = 20V$$
  
 $I_{D} = 6 A (V_{GS} = 10V)$ 

$$R_{DS(ON)} < 28m\Omega (V_{GS} = 4.5V)$$

$$R_{DS(ON)} < 38m\Omega \text{ (V}_{GS} = 2.5\text{V)}$$





Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		$V_{DS}$	20	V				
Gate-Source Voltage		$V_{GS}$	±10	V				
Continuous Drain	T <sub>A</sub> =25°C		6					
Current <sup>A</sup>		I <sub>D</sub>		А				
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	30					
	T <sub>A</sub> =25°C	P <sub>D</sub>	1.5	W				
Power Dissipation <sup>A</sup>	T <sub>A</sub> =70°C		0.96	\ \v				
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55 to 150	°C				

Thermal Characteristics									
Parameter	Symbol	Тур	Max	Units					
Maximum Junction-to-Ambient A	t ≤ 10s	В	63	83	°C/W				
Maximum Junction-to-Ambient A	Steady-State	$R_{\theta JA}$	101	130	°C/W				
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{\theta JL}$	64	83	°C/W				

#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units			
STATIC PARAMETERS									
$BV_{DSS}$	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	20			V			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V			1				
						μΑ			
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0V$ , $V_{GS}=\pm10V$			100	nA			
$BV_{GSO}$	Gate-Source Breakdown Voltage	$V_{DS}$ =0V, $I_{G}$ =±250uA	±10			V			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=1mA$	0.5	0.8	1	V			
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =5V	30			Α			
D		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A			28				
	Static Drain-Source On-Resistance	V <sub>GS</sub> =2.5V, I <sub>D</sub> =4.6A			38	m0			
R <sub>DS(ON)</sub>	Static Drain-Source On-Nesistance					mΩ			
<b>g</b> FS	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=6A$		24		S			
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V		0.7	1	V			
I <sub>S</sub>	Maximum Body-Diode Continuous Current				2.5	Α			
DYNAMIC	PARAMETERS		•	•					
C <sub>iss</sub>	Input Capacitance			630		pF			
Coss	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, f=1MHz		164		pF			
C <sub>rss</sub>	Reverse Transfer Capacitance			137		рF			
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		1.5		Ω			
SWITCHI	NG PARAMETERS								
$Q_g$	Total Gate Charge			9.3		nC			
$Q_{gs}$	Gate Source Charge	$V_{GS}$ =4.5V, $V_{DS}$ =10V, $I_{D}$ =7A		0.6		nC			
$Q_{gd}$	Gate Drain Charge			3.6		nC			
t <sub>D(on)</sub>	Turn-On DelayTime			5.7		ns			
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =5V, $V_{DS}$ =10V, $R_L$ =1.4 $\Omega$ ,		11.5		ns			
t <sub>D(off)</sub>	Turn-Off DelayTime	$R_{GEN}=3\Omega$		31.5		ns			
t <sub>f</sub>	Turn-Off Fall Time			9.7		ns			
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =7A, dI/dt=100A/μs		15.2		ns			
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =7A, dI/dt=100A/μs		6.3		nC			

A: The value of  $R_{\theta JA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C. The value in any given application depends on the user's specific board design. The currentand power rating is based on the total them.

- B: Repetitive rating, pulse width limited by junction temperature.
- C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R $_{\theta JL}$  and lead to ambient.
- D. The static characteristics in Figures 1 to 6,12,14 are obtained using  $80\mu s$  pulses, duty cycle 0.5% max.
- E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25 °C. The SOA curve provides a single pulse rating.

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#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

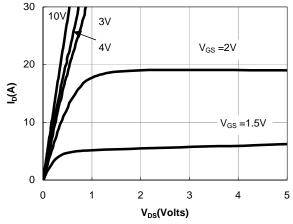


Figure 1: On-Regions CharacteristiCS

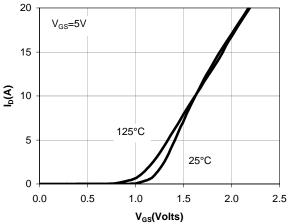


Figure 2: Transfer Characteristics

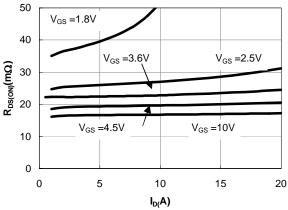


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

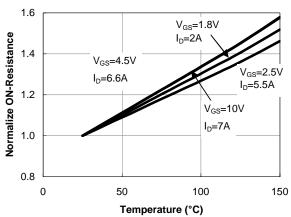


Figure 4: On-Resistance vs. Junction
Temperature

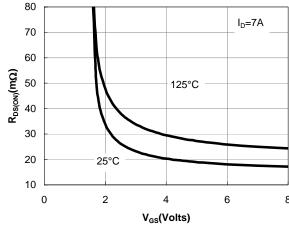


Figure 5: On-Resistance vs. Gate-Source Voltage

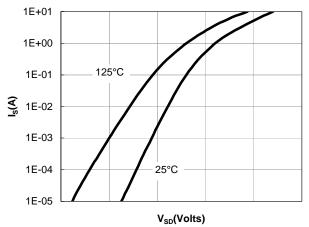


Figure 6: Body-Diode Characteristics

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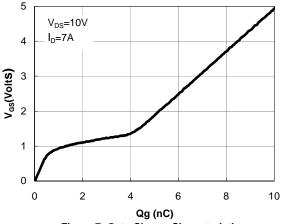


Figure 7: Gate-Charge Characteristics

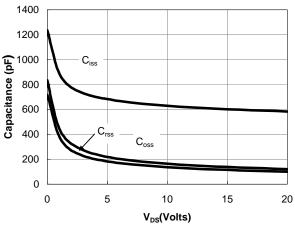


Figure 8: Capacitance Characteristics

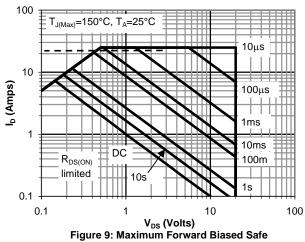


Figure 9: Maximum Forward Biased Sa Operating Area (Note E)

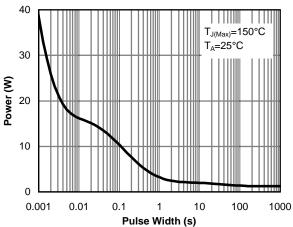


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

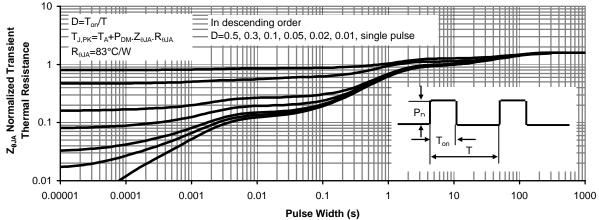


Figure 11: Normalized Maximum Transient Thermal Impedance